

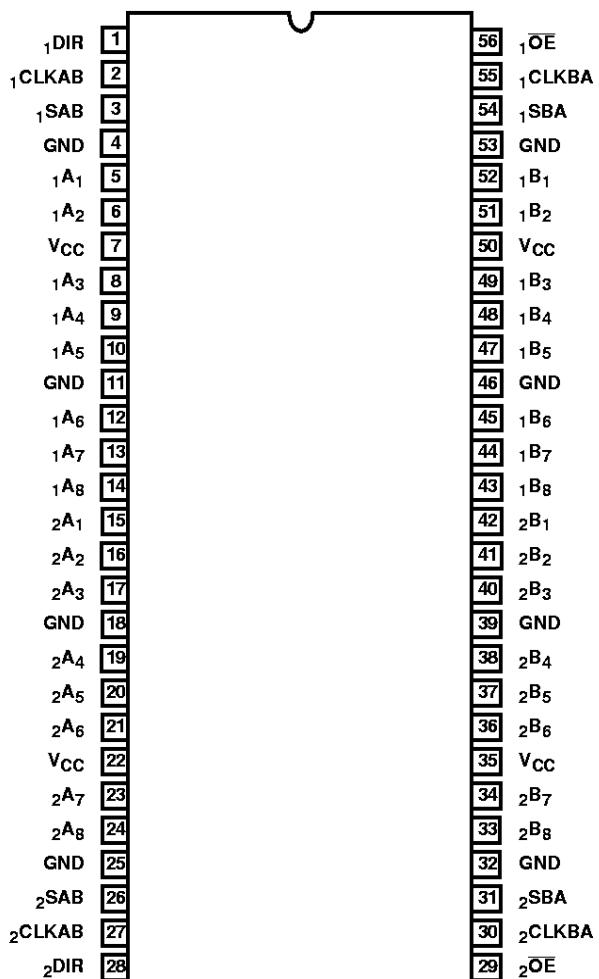
December 1997

Fast CMOS 3.3V 16-Bit Registered Transceiver

Features

- Advanced 0.6 micron CMOS Technology
- 5V Tolerant Inputs and Outputs
- Supports Live Insertion of PCBs
- 2.0V to 3.6V V_{CC} Supply Range
- Balanced 24mA Output Drive
- Low Ground Bounce Outputs
- ESD Protection Exceeds 2000V, HBM; 200V, MM
- Functionally Compatible with FCT3, LVC, LVT, and 74 Series Logic Families

Pinout

 CD74LCX16646 (SSOP, TSSOP)
 TOP VIEW


Description

Harris Semiconductor's CD74LCX16646 is produced in an advanced 0.6 micron CMOS technology, achieving industry leading speed grades.

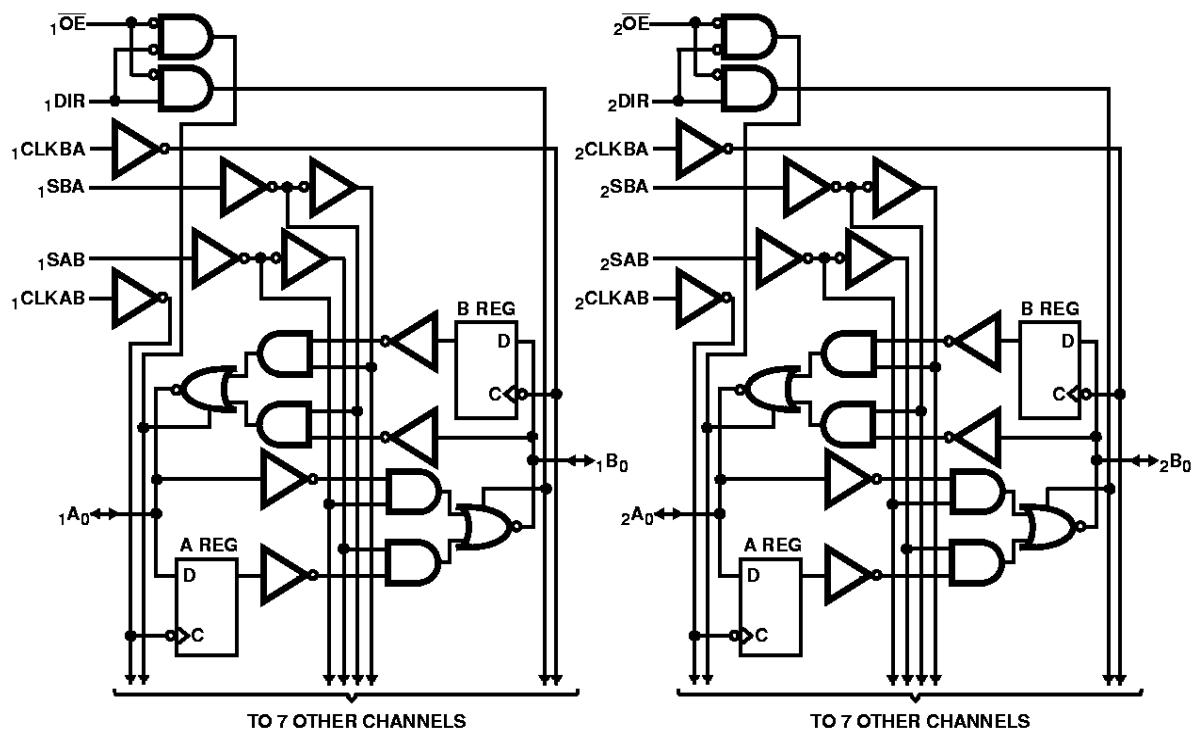
The CD74LCX16646 is a 16-bit registered transceiver organized as two independent 8-bit bus transceivers designed with three-state D-type flip-flops and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Each 8-bit transceiver utilizes the enable control ($x\bar{O}E$) and direction pins ($xDIR$) to control the transceiver functions. The Select ($xSAB$ and $xSBA$) control pins are used to select either real-time or stored data transfer. The circuitry used for select control will eliminate the typical decoding glitch that occurs in a multiplexer during the transition between real-time and stored data. A low input level selects real-time data and a high selects stored data.

The CD74LCX16646 can be driven from either 3.3V or 5.0V devices allowing this device to be used as a translator in a mixed 3.3/5.0V system.

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74LCX16646MT	-40 to 85	56 Ld TSSOP	M56.240-P
CD74LCX16646SM	-40 to 85	56 Ld SSOP	M56.300-P

NOTE: When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

Functional Block Diagram

TRUTH TABLE (NOTE 2)

FUNCTION	INPUTS						(NOTE 1) DATA I/O	
	$x\bar{OE}$	$xDIR$	$xCLKAB$	$xCLKBA$	$xSAB$	$xSBA$	xAx	xBx
Isolation Store A and B Data	H	X	H or L \uparrow	H or L \uparrow	X	X	Input	Input
Real Time B Data to A Bus Stored B Data to A Bus	L	L	X	X H or L	X	L H	Output	Input
Real Time A Data to B Bus Stored A Data to B Bus	L	H	X H or L	X	L H	X X	Input	Output

NOTES:

1. The data output functions may be enabled or disabled by various signals at the $x\bar{OE}$ or $xDIR$ inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every LOW-to-HIGH transition on the clock inputs.

2. H = High Voltage Level

L = Low Voltage Level

X = Don't Care

\uparrow = LOW-to-HIGH transition

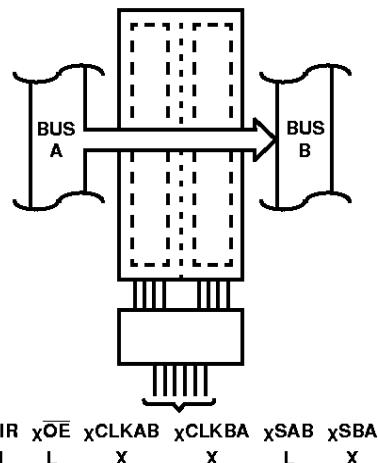
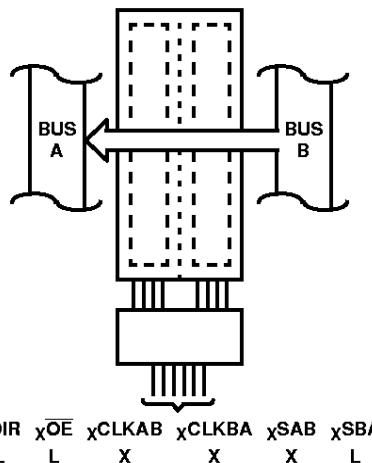


FIGURE 1. REAL-TIME TRANSFER BUS B TO A

FIGURE 2. REAL-TIME TRANSFER BUS A TO B

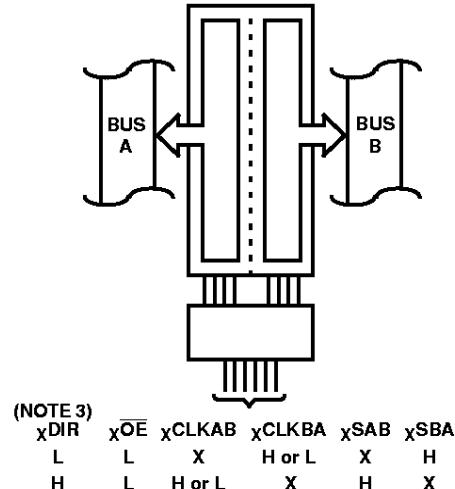
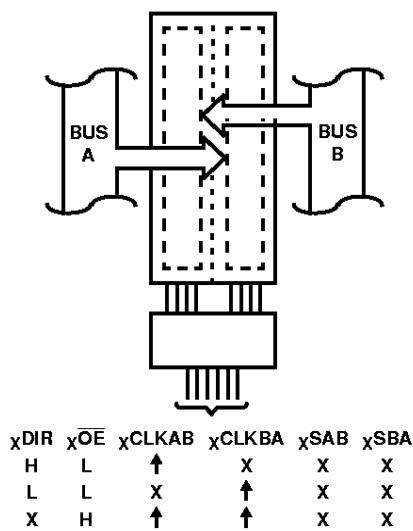


FIGURE 4. TRANSFER STORES DATA TO A AND/OR B

NOTE:

- 3. Cannot transfer data to A bus and B bus simultaneously.

Pin Descriptions

PIN NAME	DESCRIPTION
x \overline{OE} , xDIR	Output Enable Inputs (Active LOW)
xCLKAB, xCLKBA	Clock Pulse Inputs
xSAB, xSBA	Output Data Source Select Inputs
x A_x	Data Register A Inputs Data Register B Outputs
x B_x	Data Register B Inputs Data Register A Outputs
GND	Ground
V _{CC}	Power

Absolute Maximum Ratings

DC Input Voltage	-0.5V to 7.0V
DC Output Current	120mA

Operating Conditions

Temperature Range	-40°C to 85°C
Supply Voltage to Ground Potential Inputs and V_{CC} Only.....	-0.5V to 7.0V
Supply Voltage, V_{CC} Operating	2.0V (Min), 3.6V (Max)
Data Retention	1.5V (Min), 3.6V (Max)
Supply Voltage to Ground Potential Outputs and D/O Only.....	-0.5V to 7.0V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

4. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

PARAMETER	SYMBOL	(NOTE 5) TEST CONDITIONS		MIN	(NOTE 6) TYP	MAX	UNITS
DC ELECTRICAL SPECIFICATIONS Over the Operating Range, $T_A = -40^\circ\text{C}$ to 85°C , $V_{CC} = 2.7\text{V}$ to 3.6V							
Input HIGH Voltage	V_{IH}	Guaranteed Logic HIGH Level		2.0	-	-	V
Input LOW Voltage (Input and I/O Pins)	V_{IL}	Guaranteed Logic LOW Level		-	-	0.8	V
Output HIGH Voltage	V_{OH}	$V_{CC} = 2.7\text{V}$ to 3.6V	$I_{OH} = -0.1\text{mA}$	$V_{CC} - 0.2$	-	-	V
		$V_{CC} = 2.7\text{V}$	$I_{OH} = -12\text{mA}$	2.2	-	-	V
		$V_{CC} = 3.0\text{V}$	$I_{OH} = -18\text{mA}$	2.4	-	-	V
			$I_{OH} = -24\text{mA}$	2.2	-	-	V
Output LOW Voltage	V_{OL}	$V_{CC} = 2.7\text{V}$ to 3.6V	$I_{OL} = 0.1\text{mA}$	-	-	0.2	V
		$V_{CC} = 2.7\text{V}$	$I_{OL} = 12\text{mA}$	-	-	0.4	V
		$V_{CC} = 3\text{V}$	$I_{OL} = 16\text{mA}$	-	-	0.4	V
			$I_{OL} = 24\text{mA}$	-	-	0.55	V
Clamp Diode Voltage	V_{IK}	$V_{CC} = \text{Min}$, $I_{IN} = -18\text{mA}$		-	-0.7	-1.2	V
Input Current	I_I	$V_{CC} = 2.7\text{V}$ to 3.6V	$0 \leq V_I \leq 5.5\text{V}$	-	-	± 5	μA
High Impedance Output Current (Three-State)	I_{OZ}	$V_{CC} = 2.7\text{V}$ to 3.6V	$0 \leq V_O \leq 5.5\text{V}$ $V_I = V_{IH}$ or V_{IL}	-	-	± 5	μA
Power Down Disable	I_{OFF}	$V_{CC} = 0\text{V}$	V_{IN} or $V_{OUT} \leq 5.5\text{V}$	-	-	10	μA
Quiescent Power Supply Current	I_{CC}	$V_{CC} = \text{Max}$	$V_{IN} = \text{GND}$ or V_{CC}	-	0.1	10	μA
Quiescent Power Supply Current TTL Inputs HIGH	ΔI_{CC}	$V_{CC} = \text{Max}$	$V_{IN} = V_{CC} - 0.6\text{V}$ (Note 7)	-	-	500	μA
CAPACITANCE							
Input Capacitance (Note 8)	C_{IN}	$V_{CC} = \text{Open}$, $V_{IN} = 0\text{V}$ or V_{CC}		-	7	-	pF
Output Capacitance (Note 8)	C_{OUT}	$V_{CC} = 3.3\text{V}$, $V_{IN} = 0\text{V}$ or V_{CC}		-	8	-	pF
Power Dissipation Capacitance (Note 9)	C_{PD}	$V_{CC} = 3.3\text{V}$, $V_{IN} = 0\text{V}$ or V_{CC} , $f = 10\text{MHz}$		-	20	-	pF

Thermal Information

Thermal Resistance (Typical, Note 4)	θ_{JA} ($^\circ\text{C}/\text{W}$)
TSSOP Package	85
SSOP Package	70
Maximum Junction Temperature	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C (Lead Tips Only)

Switching Specifications Over Operating Range

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} = 3.3V ± 0.3V		V _{CC} = 2.7V		UNITS
			MIN	MAX	MIN	MAX	
Maximum Clock Frequency	f _{MAX}	C _L = 50pF, R _L = 500Ω	170	-	-	-	MHz
Propagation Delay, Bus to Bus	t _{PHL} , t _{PLH}		1.5	5.0	1.5	6.0	ns
Propagation Delay, Clock to Bus	t _{PHL} , t _{PLH}		1.5	6.0	1.5	7.0	ns
Propagation Delay, Select to Bus	t _{PHL} , t _{PLH}		1.5	6.0	1.5	7.0	ns
Output Enable Time	t _{PZL} , t _{PZH}		1.5	7.5	1.5	8.5	ns
Output Disable Time (Note 12)	t _{PLZ} , t _{PHZ}		1.5	6.0	1.5	7.0	ns
Setup Time	t _S		2.5	-	2.5	-	ns
Hold Time	t _H		1.5	-	1.5	-	ns
Pulse Width (Note 12)	t _W		3.0	-	3.0	-	ns
Output to Output Skew (Note 13)	t _{SK(O)}		-	1.0	-	-	ns

Dynamic Switching Characteristics T_A = 25°C

PARAMETER	SYMBOL	(NOTE 14) TEST CONDITIONS	TYP	UNITS
Dynamic LOW Peak Voltage	V _{OLP}	V _{CC} = 3.3V, C _L = 50pF, V _{IH} = 3.3V, V _{IL} = 0V	0.8	V
Dynamic LOW Valley Voltage	V _{OLV}	V _{CC} = 3.3V, C _L = 50pF, V _{IH} = 3.3V, V _{IL} = 0V	0.8	V

NOTES:

5. For conditions shown as Max or Min, use appropriate value specified under Electrical Specifications for the applicable device type.
6. Typical values are at V_{CC} = 3.3V, 25°C ambient and maximum loading.
7. Per TTL driven input; all other inputs at V_{CC} or GND.
8. This parameter is determined by device characterization but is not production tested.
9. C_{PD} determines the no-load dynamic power consumption per latch. It is obtained by the following relationship:

$$P_D \text{ (total power per latch)} = V_{CC}^2 f_i (C_{PD} + C_L) \text{ where } f_i = \text{input frequency}, C_L = \text{output load capacitance}, V_{CC} = \text{supply range.}$$
10. See test circuit and waveforms.
11. Minimum limits are guaranteed but not tested on Propagation Delays.
12. This parameter is guaranteed but not production tested.
13. Skew between any two outputs, of the same package, switching in the same direction. This parameter is guaranteed by design.
14. Measured with n-1 outputs switching from High-to-Low or Low-to-High. The remaining output is measured in the LOW state.